

Search Notes

Application/Control No.

09/916,095

Examiner

Quoc A. Tran

Applicant(s)/Patent under
Reexamination

CHINN ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
707	100	7/16/2005	<i>[Signature]</i>
707	102	7/16/2005	<i>[Signature]</i>
704	270	7/16/2005	<i>[Signature]</i>
379	88.2	7/16/2005	<i>[Signature]</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	7/16/2005	<i>[Signature]</i>
EAST (US-PAT, US-PGPUB)see (see Search Histoty Printout)	7/16/2005	<i>[Signature]</i>
NPL IEEE DataBasesee Search (see History Printout)	7/16/2005	<i>[Signature]</i>
Altavista DataBase (see History Prinout)	7/16/2005	<i>[Signature]</i>
Plus Search for Classification (see History Prinout)	7/16/2005	<i>[Signature]</i>